Hex D-type flip-flop Rev. 7 — 21 November 2011

Product data sheet

1. **General description**

The HEF40174B is a hex edge-triggered D-type flip-flop with six data inputs (D0 to D5), a clock input (CP), an overriding asynchronous master reset input (MR), and six buffered outputs (Q0 to Q5). Information on D0 to D5 is transferred to Q0 to Q5 on the LOW-to-HIGH transition of CP if MR is HIGH. When LOW, MR resets all flip-flops (Q0 to Q5 = LOW) independent of CP and D0 to D5.

It operates over a recommended V_{DD} power supply range of 3 V to 15 V referenced to V_{SS} (usually ground). Unused inputs must be connected to V_{DD}, V_{SS}, or another input.

Features and benefits 2.

- Fully static operation
- 5 V, 10 V, and 15 V parametric ratings
- Standardized symmetrical output characteristics
- Specified from –40 °C to +85 °C
- Complies with JEDEC standard JESD 13-B

Applications

- Shift registers
- Buffer/storage register
- Pattern generator

Ordering information 4.

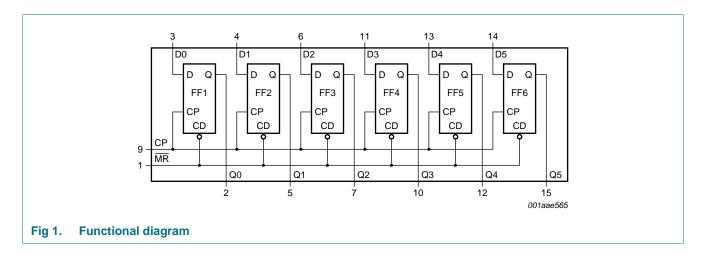
Table 1. **Ordering information**

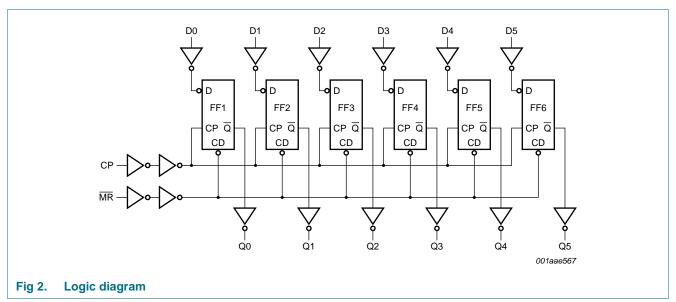
All types operate from -40 °C to +85 °C.

Type number	Package									
	Name	Description	Version							
HEF40174BP	DIP16	plastic dual in-line package; 16 leads (300 mil)	SOT38-4							
HEF40174BT	SO16	plastic small outline package; 16 leads; body width 3.9 mm	SOT109-1							



5. Functional diagram

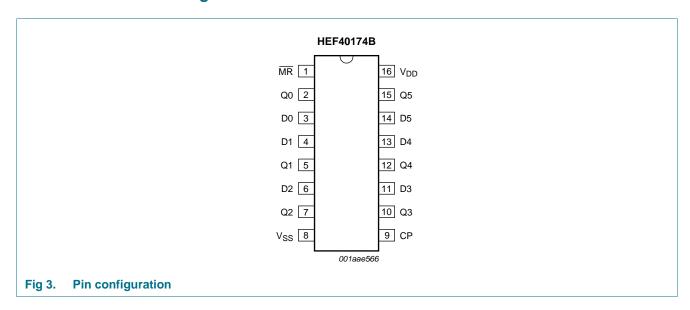




Hex D-type flip-flop

6. Pinning information

6.1 Pinning



6.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
MR	1	master reset input (active LOW)
Q0, Q1, Q2, Q3, Q4, Q5	2, 5, 7, 10, 12, 15	buffered output
D0, D1, D2, D3, D4, D5	3, 4, 6, 11, 13, 14	data input
V _{SS}	8	ground supply voltage
СР	9	clock input (LOW-to-HIGH; edge-triggered)
V_{DD}	16	supply voltage

7. Functional description

Table 3. Function table[1]

Input CP			Output
СР	D	MR	Q
\uparrow	Н	Н	Н
\uparrow	L	Н	L
	X	Н	no change
X	X	L	L

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; $\uparrow = positive-going transition$; $\downarrow = negative-going transition$.

8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DD}	supply voltage		-0.5	+18	V
I_{IK}	input clamping current	$V_I < -0.5 \text{ V or } V_I > V_{DD} + 0.5 \text{ V}$	-	±10	mA
V_{I}	input voltage		-0.5	$V_{DD} + 0.5$	V
I _{OK}	output clamping current	$V_O < -0.5 \text{ V or } V_O > V_{DD} + 0.5 \text{ V}$	-	±10	mA
I _{I/O}	input/output current		-	±10	mA
I_{DD}	supply current		-	50	mA
T _{stg}	storage temperature		-65	+150	°C
T _{amb}	ambient temperature		-40	+85	°C
P _{tot}	total power dissipation	DIP16 package	[1] _	750	mW
		SO16 package	[2] _	500	mW
Р	power dissipation	per output	-	100	mW

^[1] For DIP16 package: P_{tot} derates linearly with 12 mW/K above 70 °C.

9. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DD}	supply voltage		3	-	15	V
VI	input voltage		0	-	V_{DD}	V
T _{amb}	ambient temperature	in free air	-40	-	+85	°C
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{DD} = 5 V$	-	-	3.75	μs/V
		$V_{DD} = 10 \text{ V}$	-	-	0.5	μs/V
		$V_{DD} = 15 \text{ V}$	-	-	0.08	μs/V

10. Static characteristics

Table 6. Static characteristics

 $V_{SS} = 0 \ V$; $V_I = V_{SS} \ or \ V_{DD} \ unless \ otherwise \ specified.$

Symbol	Parameter	Conditions	V_{DD}	T _{amb} =	–40 °C	T _{amb} = 25 °C		T _{amb} = 85 °C		Unit
				Min	Max	Min	Max	Min	Max	
V _{IH}	HIGH-level input voltage	I _O < 1 μA	5 V	3.5	-	3.5	-	3.5	-	V
			10 V	7.0	-	7.0	-	7.0	-	V
			15 V	11.0	-	11.0	-	11.0	-	V
V_{IL}	LOW-level input voltage	I _O < 1 μA	5 V	-	1.5	-	1.5	-	1.5	V
			10 V	-	3.0	-	3.0	-	3.0	V
			15 V	-	4.0	-	4.0	-	4.0	V

^[2] For SO16 package: Ptot derates linearly with 8 mW/K above 70 °C.

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 Table 6.
 Static characteristics ...continued

 $V_{SS} = 0$ V; $V_I = V_{SS}$ or V_{DD} unless otherwise specified.

Symbol	Parameter	Conditions	V_{DD}	T _{amb} =	-40 °C	T _{amb} =	25 °C	T _{amb} =	85 °C	Unit
				Min	Max	Min	Max	Min	Max	
V _{OH}	HIGH-level output voltage	$ I_{O} < 1 \mu A$	5 V	4.95	-	4.95	-	4.95	-	V
			10 V	9.95	-	9.95	-	9.95	-	V
			15 V	14.95	-	14.95	-	14.95	-	V
V _{OL}	LOW-level output voltage	$ I_{O} < 1 \mu A$	5 V	-	0.05	-	0.05	-	0.05	V
			10 V	-	0.05	-	0.05	-	0.05	V
			15 V	-	0.05	-	0.05	-	0.05	V
I _{OH}	HIGH-level output current	$V_0 = 2.5 \text{ V}$	5 V	-	-1.7	-	-1.4	-	-1.1	mΑ
		$V_0 = 4.6 \text{ V}$	5 V	-	-0.52	-	-0.44	-	-0.36	mΑ
		$V_0 = 9.5 \ V$	10 V	-	-1.3	-	-1.1	-	-0.9	mΑ
		$V_0 = 13.5 \text{ V}$	15 V	-	-3.6	-	-3.0	-	-2.4	mΑ
I _{OL}	LOW-level output current	$V_0 = 0.4 \ V$	5 V	0.52	-	0.44	-	0.36	-	mΑ
		$V_0 = 0.5 \ V$	10 V	1.3	-	1.1	-	0.9	-	mΑ
		$V_0 = 1.5 \text{ V}$	15 V	3.6	-	3.0	-	2.4	-	mΑ
I _I	input leakage current		15 V	-	±0.3	-	±0.3	-	±1.0	μΑ
I _{DD}	supply current	I _O = 0 A	5 V	-	20	-	20	-	150	μΑ
			10 V	-	40	-	40	-	300	μΑ
			15 V	-	80	-	80	-	600	μΑ
Cı	input capacitance		-	-	-	-	7.5	-	-	pF

11. Dynamic characteristics

Table 7. Dynamic characteristics

 $V_{SS} = 0 \text{ V}$; $T_{amb} = 25 \text{ °C}$; or test circuit see <u>Figure 5</u>; unless otherwise specified.

Symbol	Parameter	Conditions	V_{DD}	Extrapolation formula	Min	Тур	Max	Unit
t_{PHL}	HIGH to LOW	CP to Qn;	5 V	48 ns + (0.55 ns/pF)C _L	-	75	155	ns
	propagation delay	see <u>Figure 4</u>	10 V	19 ns + (0.23 ns/pF)C _L	-	30	65	ns
			15 V	12 ns + (0.16 ns/pF)C _L	-	20	45	ns
		MR to Qn;	5 V	58 ns + (0.55 ns/pF)C _L	-	85	175	ns
		see Figure 4	10 V	24 ns + (0.23 ns/pF)C _L	-	35	70	ns
			15 V	17 ns + (0.16 ns/pF)C _L	-	25	50	ns
t _{PLH}	LOW to HIGH	CP to Qn;	5 V	48 ns + (0.55 ns/pF)C _L	-	75	155	ns
	propagation delay	see Figure 4	10 V	19 ns + (0.23 ns/pF)C _L	-	30	65	ns
			15 V	12 ns + (0.16 ns/pF)C _L	-	20	45	ns
t _t	transition time	see Figure 4	5 V	10 ns + (1.00 ns/pF)C _L	-	60	120	ns
			10 V	9 ns + (0.42 ns/pF)C _L	-	30	60	ns
			15 V	6 ns + (0.28 ns/pF)C _L	-	20	40	ns
t _{su}	set-up time	Dn to CP;	5 V		20	10	-	ns
		see Figure 4	10 V		10	5	-	ns
			15 V		10	5	-	ns

 Table 7.
 Dynamic characteristics ...continued

 $V_{SS} = 0 \text{ V}$; $T_{amb} = 25 \text{ °C}$; or test circuit see <u>Figure 5</u>; unless otherwise specified.

Symbol	Parameter	Conditions	V_{DD}	Extrapolation formula	Min	Тур	Max	Unit
t_h	hold time	Dn to CP;	5 V		10	0	-	ns
		see Figure 4	10 V		5	0 - 0 - 0 - 35 - 15 - 10 - 35 - 110 - 25 - 10 - 5 -	ns	
			15 V		5	0	-	ns
t_{W}	pulse width	CP input LOW;	5 V		70	35	- n:	ns
		minimum width; see Figure 4	10 V		30	15	-	ns
		see <u>rigure 4</u>	15 V		20	10	- I	ns
		MR input LOW; minimum width;	5 V		70	35	-	ns
			10 V		35	15	-	ns
		see Figure 4	15 V		25	10	-	ns
t _{rec}	recovery time	MR input;	5 V		45	25	-	ns
		see Figure 4	10 V		20	10	-	ns
			15 V		15	5	-	ns
f _{max}	maximum frequency	see Figure 4	5 V		5	11	-	MHz
'max			10 V		15	30	-	MHz
			15 V		20	45	-	MHz

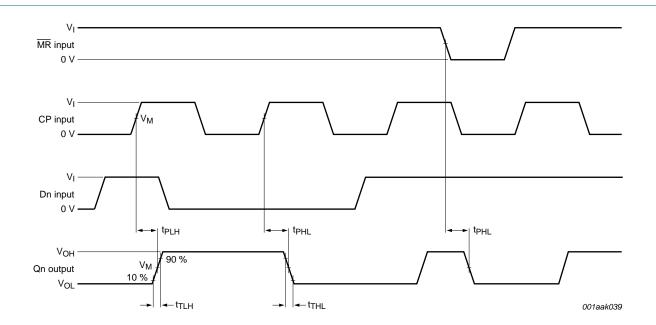
^[1] t_t is the same as t_{THL} and t_{TLH} .

Table 8. Dynamic power dissipation P_D

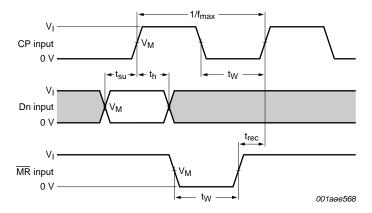
 P_D can be calculated from the formulas shown. $V_{SS} = 0 \text{ V}$; $t_r = t_f \le 20 \text{ ns}$; $T_{amb} = 25 \text{ }^{\circ}\text{C}$.

Symbol	Parameter	V_{DD}	Typical formula for P _D (μW)	where:
P_D	dynamic power	5 V	$P_D = 3500 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2$	f_i = input frequency in MHz,
	dissipation	10 V	$P_D = 16000 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2$	fo = output frequency in MHz,
		15 V	$P_D = 42000 \times f_i + \Sigma (f_0 \times C_L) \times V_{DD}^2$	C_L = output load capacitance in pF,
				V_{DD} = supply voltage in V,
				Σ (f _o × C _L) = sum of the outputs.

12. Waveforms



a. CP and MR to Qn Propagation delays and Qn transition times



b. CP and MR minimum pulse widths, MR to CP recovery time, and Dn to CP set-up and hold times

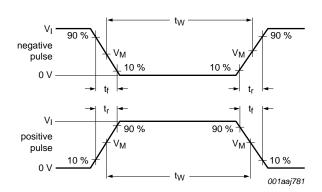
 $\ensuremath{V_{\text{OH}}}$ and $\ensuremath{V_{\text{OL}}}$ are typical output voltage levels that occur with the output load.

Set-up and hold times are shown as positive values but may be specified as negative values.

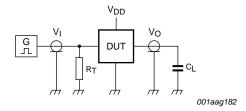
The shaded area are where input changes result in predicable output performance.

Measurement points are given in Table 9.

Fig 4. Waveforms showing switching times



a. Input waveforms



b. Test circuit

Test data is given in Table 9.

Definitions for test circuit:

DUT = Device Under Test

C_L = Load capacitance including jig and probe capacitance;

 R_T = Termination resistance should be equal to output impedance Z_0 of the pulse generator.

Fig 5. Test circuit for measuring switching times

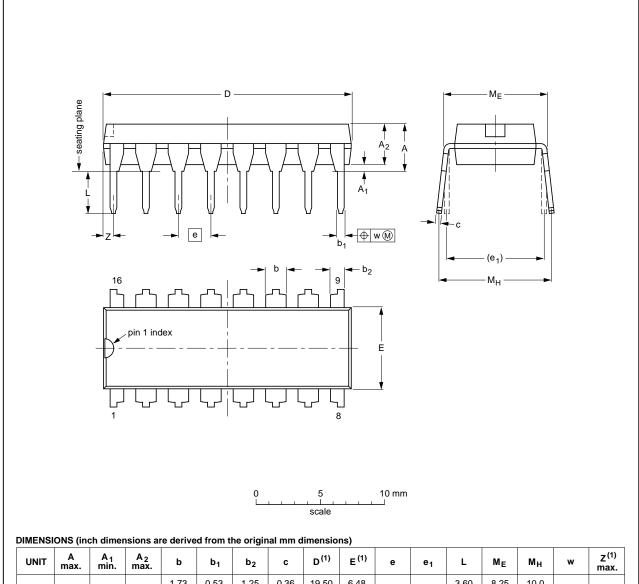
Table 9. Measurement points and test data

Supply voltage	Input			Load
	VI	V _M	t _r , t _f	CL
5 V to 15 V	V_{DD}	0.5V _I	≤ 20 ns	50 pF

13. Package outline

DIP16: plastic dual in-line package; 16 leads (300 mil)

SOT38-4



UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	b ₂	С	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	ME	Мн	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	1.25 0.85	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	0.76
inches	0.17	0.02	0.13	0.068 0.051	0.021 0.015	0.049 0.033	0.014 0.009	0.77 0.73	0.26 0.24	0.1	0.3	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.03

Note

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN	ISSUE DATE
	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT38-4						95-01-14 03-02-13

Fig 6. Package outline SOT38-4 (DIP16)

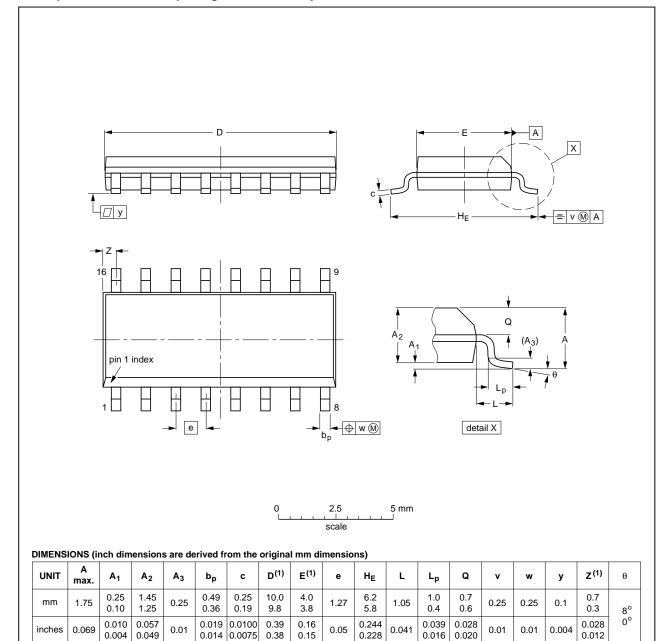
HEF40174B

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SO16: plastic small outline package; 16 leads; body width 3.9 mm

SOT109-1



Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE	REFERENCES			EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT109-1	076E07	MS-012				99-12-27 03-02-19

Fig 7. Package outline SOT109-1 (SO16)

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14. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
HEF40174B v.7	20111121	Product data sheet	-	HEF40174B v.6
Modifications:	 Legal pages 	s updated.		
	 Changes in 	"General description", "Fea	tures and benefits" and	"Applications".
HEF40174B v.6	20110914	Product data sheet	-	HEF40174B v.5
HEF40174B v.5	20100106	Product data sheet	-	HEF40174B v.4
HEF40174B v.4	20090813	Product data sheet	-	HEF40174B_CNV v.3
HEF40174B_CNV v.3	19950101	Product specification	-	HEF40174B_CNV v.2
HEF40174B_CNV v.2	19950101	Product specification	-	-

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15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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